

TP3076 COMBO[®] II Programmable PCM CODEC/Filter for ISDN and Digital Phone Applications

Check for Samples: TP3076

FEATURES

- Complete CODEC and Filter system including:
 - Transmit and receive PCM channel filters
 - µ-law or A-law companding coder and decoder
 - Receive power amplifier drives 300Ω
 - 4.096 MHz serial PCM data (max)
- **Programmable functions:**
 - Transmit gain: 25.4 dB range, 0.1 dB steps
 - Receive gain: 25.4 dB range, 0.1 dB steps
 - Time-slot assignment; to 64 slots/frame

- 4 interface latches
- A or µ-law
- Analog loopback
- Digital loopback
- Direct interface to solid-state SLICs
- Standard serial control interface •
- 80 mW operating power (typ)
- ٠ 1.5 mW standby power (typ)
- Designed for CCITT and LSSGR specifications
- TTL and CMOS compatible digital interfaces

DESCRIPTION

The TP3076 is a second-generation combined PCM CODEC and Filter devices optimized for digital switching applications on subscriber line and trunk cards and digital phone applications. Using advanced switched capacitor techniques, COMBO II combines transmit bandpass and receive lowpass channel filters with a companding PCM encoder and decoder. The devices are A-law and µ-law selectable and employ a conventional serial PCM interface capable of being clocked up to 4.096 MHz. A number of programmable functions may be controlled via a serial control port.

Channel gains are programmable over a 25.4 dB range in each direction.

To enable COMBO II to interface to the SLIC control leads, a number of programmable latches are included; each may be configured as either an input or an output. The TP3076 provides 4 latches.

AA

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

NOTE

See also AN-614 COMBO II application guide.

Absolute Maximum Ratings ⁽¹⁾

5	
V _{CC} to GND	7V
Voltage at VF _X I	V_{CC} +0.5V to V_{BB} =0.5V
Voltage at Any Digital Input	V _{CC} +0.5V to GND −0.5V
Storage Temperature Range	−65°C to +150°C
V _{BB} to GND	-7V
Current at VF _R 0	±100 mA
Current at Any Digital Output	±50 mA
Lead Temperature	
(Soldering, 10 sec.)	300°C

(1) "Absolute Maximum Ratings" indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet. COMBO, TRI-STATE are registered trademarks of Texas Instruments. MICROWIRE/PLUS, COMBO II are trademarks of dcl_owner. All other trademarks are the property of their respective owners.



SNOSC47C - MAY 2004 - REVISED JANUARY 2010

Electrical Characteristics

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for $V_{CC} = +5V \pm 5\%$, $V_{BB} = -5V \pm 5\%$; $T_A = 0^{\circ}C$ to +70°C by correlation with 100% electrical testing at $T_A = 25^{\circ}C$. All other limits are assured by correlation with other production tests and/or product design and characterization. All signals referenced to GND. Typicals specified at $V_{CC} = +5V$, $V_{BB} = -5V$, $T_A = 25^{\circ}C$.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
DIGITAL I	NTERFACES					
V _{IL}	Input Low Voltage ⁽¹⁾	All Digital Inputs (DC Meas.)			0.7	V
V _{IH}	Input High Voltage ⁽¹⁾	All Digital Inputs (DC Meas.) (2)	2.0			V
V _{OL}	Output Low Voltage	$D_X 1$, $\overline{TS}_X 1$, and CO, $I_L = 3.2 \text{ mA}$,			0.4	V
		All Other Digital Outputs, $I_L = 1 \text{ mA}$				
V _{OH}	Output High Voltage	D_X1 and CO, $I_L = -3.2$ mA,	2.4			V
		All Other Digital Outputs (except \overline{TS}_X), $I_L = -1 \text{ mA}$				
		All Digital Outputs, I _L = −100 µA	V _{CC} - 0.5			V
I _{IL}	Input Low Current	Any Digital Input, GND < V _{IN} < V _{IL}	-10		10	μA
I _{IH}	Input High Current	Any Digital Input, except MR, V _{IH} < V _{IN} < V _{CC}	-10		10	μA
		MR Only	-10		100	
l _{oz}	Output Current in	D_X1 , \overline{TS}_{X1} and CO				
	High Impedance	IL3–IL0 when Selected as Inputs	-10		10	μA
	State (TRI-STATE [®])	GND < V _{OUT} < V _{CC}				
ANALOG	INTERFACES				1	
I _{VFXI}	Input Current, VF _X I	−3.3V < VF _X I < 3.3V	-1.0		1.0	μA
R _{VFXI}	Input Resistance	-3.3V < VF _X I < 3.3V	1.0			MΩ
VOS _X	Input Offset Voltage	Transmit Gain = 0 dB			200	mV
	Applied at VF _X I	Transmit Gain = 25.40 dB			10	mV
RL _{VFRO}	Load Resistance	Receive Gain = 0 dB	15k			
		Receive Gain = -0.5 dB	600			Ω
		Receive Gain = −1.2 dB	300			
CL _{VFRO}	Load Capacitance	RL _{VFRO} ≥ 300Ω			200	pF
		CL _{VFRO} from VF _R O to GND				
RO _{VFRO}	Output Resistance	Steady Zero PCM Code Applied to D _R 1		1.0	3.0	Ω
VOS _R	Output Offset Voltage	Alternating ± Zero PCM Code Applied	-200		200	mV
	at V _{FRO}	D _R 1, Maximum Receive Gain				
POWER D	ISSIPATION					
I _{CC} 0	Power Down Current	CCLK, CI, CO = $0.4V$, $\overline{CS} = 2.4V$				
		Interface Latches Set as Outputs with No Load,		0.1	0.6	mA
		All Other Inputs Active, Power Amp Disabled				
I _{BB} 0	Power Down Current	As Above		-0.1	-0.3	mA
I _{CC} 1	Power Up Current	CCLK, CI, CO = $0.4V$, $\overline{CS} = 2.4V$				
		No Load on Power Amp		8.0	11.0	mA
		Interface Latches Set as Outputs with No Load				
I _{BB} 1	Power Up Current	As Above		-8.0	-11.0	mA
I _{CC} 2	Power Down Current	As Above, Power Amp Enabled		2.0	3.0	mA
I _{BB} 2	Power Down Current	As Above, Power Amp Enabled		-2.0	-3.0	mA

(1) A signal is Valid if it is above V_{IH} or below V_{IL} and Invalid if it is between V_{IL} and V_{IH} . For the purposes of this specification the following conditions apply: a) All input signals are defined as: $V_{IL} = 0.4V$, $V_{IH} = 2.7V$, $t_R < 10$ ns, $t_F < 10$ ns. b) t_R is measured from V_{IL} to V_{IH} . c) Delay Times are measured from the input signal Valid to the output signal Valid. d) Setup Times are measured from the data input Valid to the clock input Invalid. e) Hold Times are measured from the clock signal Valid to the data input Invalid. f) Pulse widths are measured from V_{IL} to V_{IL} or from V_{IL} to V_{IH} .

(2) See definitions and timing conventions section.



www.ti.com

Timing Specifications

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for $V_{CC} = +5V \pm 5\%$; $V_{BB} = -5V \pm 5\%$; $T_A = 0^{\circ}C$ to +70°C by correlation with 100% electrical testing at $T_A = 25^{\circ}C$. All other limits are assured by correlation with other production tests and/or product design and characterization. All signals referenced to GND. Typicals specified at $V_{CC} = +5V$, $V_{BB} = -5V$, $T_A = 25^{\circ}C$.

All timing parameters are measured at V_{OH} = 2.0V and V_{OL} = 0.7V.

See Definitions and Timing Conventions section for test methods information.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
MASTER	CLOCK TIMING				I	1
f _{MCLK}	Frequency of MCLK	Selection of Frequency is Programmable		512		kHz
		(See Table 5)		1536		kHz
				1544		kHz
				2048		kHz
				4096		kHz
t _{WMH}	Period of MCLK High	Measured from V _{IH} to V _{IH} ⁽¹⁾	80			ns
t _{WML}	Period of MCLK Low	Measured from V_{IL} to $V_{IL}^{(1)}$	80			ns
t _{RM}	Rise Time of MCLK	Measured from V _{IL} to V _{IH}			30	ns
t _{FM}	Fall Time of MCLK	Measured from V _{IH} to V _{IL}			30	ns
t _{HBM}	HOLD Time, BCLK LOW		50			ns
	to MCLK HIGH					
t _{WFL}	Period of FS _X	Measured from V _{IL} to V _{IL}	1			MCLK
	or FS _R Low					Period
PCM INT	ERFACE TIMING		L	I	I	I
f _{BCLK}	Frequency of BCLK	May Vary from 64 kHz to 4096 kHz	64		4096	kHz
		in 8 kHz Increments				
t _{WBH}	Period of BCLK High	Measured from V _{IH} to V _{IH}	80			ns
t _{WBL}	Period of BCLK Low	Measured from V _{IL} to V _{IL}	80			ns
t _{RB}	Rise Time of BCLK	Measured from V _{IL} to V _{IH}			30	ns
t _{FB}	Fall Time of BCLK	Measured from V _{IH} to V _{IL}			30	ns
t _{HBF}	Hold Time, BCLK Low		30			ns
	to FS _{X/R} High or Low					
t _{SFB}	Setup Time, FS _{X/R}		30			ns
-	High to BCLK Low					
t _{DBD}	Delay Time, BCLK High	Load = 100 pF Plus 2 LSTTL Loads			80	ns
	to Data Valid					
t _{DBZ}	Delay Time, BCLK Low to D _X 1	D _X 1 disabled is measured				
	Disabled if FS _X Low, FS _X Low to	at V _{OL} or V _{OH} according				
	D _X 1 disabled if 8th BCLK	to Figure 3	15		80	ns
	Low, or BCLK High to D _X 1					
	Disabled if FS _X High					
t _{DBT}	Delay Time, BCLK High to	Load = 100 pF Plus 2 LSTTL Loads				
	\overline{TS}_{X} Low if FS_{X} High, or				60	ns
	FS_X High to \overline{TS}_X Low if					
	BCLK High (Nondelayed mode); BCLK					
	High to \overline{TS}_X Low (delayed data mode)					
t _{ZBT}	TRI-STATE Time, BCLK Low to					
	\overline{TS}_{X} High if FS_{X} Low, FS_{X} Low					
	to TS _X High if 8th BCLK Low, or		15		60	ns
	BCLK High to \overline{TS}_X High if FS _X High					

(1) Applies only to MCLK Frequencies ≥ 1.536 MHz. At 512 kHz a 50:50 ±2% Duty Cycle must be used.



SNOSC47C - MAY 2004 - REVISED JANUARY 2010

Timing Specifications (continued)

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for $V_{CC} = +5V \pm 5\%$; $V_{BB} = -5V \pm 5\%$; $T_A = 0^{\circ}C$ to +70°C by correlation with 100% electrical testing at $T_A = 25^{\circ}C$. All other limits are assured by correlation with other production tests and/or product design and characterization. All signals referenced to GND. Typicals specified at $V_{CC} = +5V$, $V_{BB} = -5V$, $T_A = 25^{\circ}C$.

All timing parameters are measured at $V_{OH} = 2.0V$ and $V_{OL} = 0.7V$.

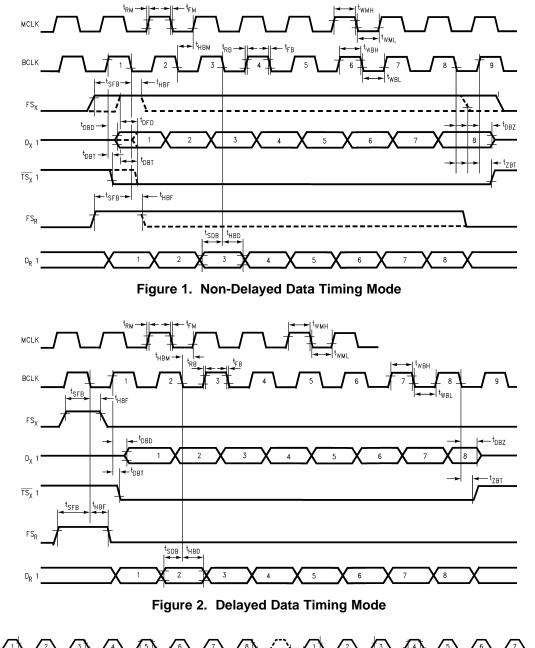
See Definitions and Timing Conventions section for test methods information.

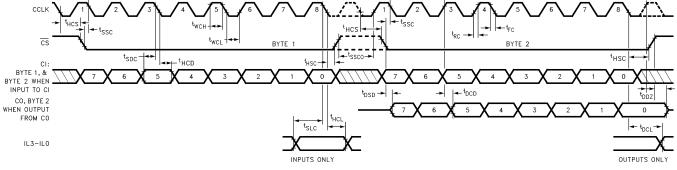
Symbol	Parameter	Conditions	Min	Тур	Max	Units
t _{DFD}	Delay Time, FS _{X/R}	Load = 100 pF Plus 2 LSTTL Loads,				
	High to Data Valid	Applies if FS _{X/R} Rises Later Than			80	ns
		BCLK Rising Edge in Non-Delayed Data				
		Mode Only				
t _{SDB}	Setup Time, D _R 1		30			ns
	Valid to BCLK Low					
t _{HBD}	Hold Time, BCLK		15			ns
	Low to D _R 1 Invalid					
SERIAL C	ONTROL PORT TIMING					
f _{CCLK}	Frequency of CCLK				2048	kHz
t _{WCH}	Period of CCLK High	Measured from V _{IH} to V _{IH}	160			ns
t _{WCL}	Period of CCLK Low	Measured from VIL to VIH	160			ns
t _{RC}	Rise Time of CCLK	Measured from V_{IL} to V_{IH}			50	ns
t _{FC}	Fall Time of CCLK	Measured of V _{IH} to V _{IL}			50	ns
t _{HCS}	Hold Time, CCLK Low	CCLK1	10			ns
	to CS Low					
t _{HSC}	Hold Time, CCLK	CCLK8	100			ns
	Low to CS High					
t _{SSC}	Setup Time, CS		60			ns
	Transition to CCLK Low					
t _{SSC0}	Setup Time, CS	To Insure CO is Not Enabled	60			ns
	Transition to CCLK High	for Single Byte				
t _{SDC}	Setup Time, CI		50			ns
	Data In to CCLK Low					
t _{HCD}	Hold Time, CCLK		50			ns
	Low to CO Invalid					
t _{DCD}	Delay Time, CCLK High	Load = 100 pF Plus 2 LSTTL Loads			80	ns
-	to CO Data Out Valid					
t _{DSD}	Delay Time, CS Low	Applies Only if Separate			80	ns
-	to CO Valid	CS Used for Byte 2				
t _{DDZ}	Delay Time, CS or 9th CCLK	Applies to Earlier of CS	15		80	ns
	High to CO High Impedance	High or 9th CCLK High				
INTERFA	CE LATCH TIMING				ļ	
t _{SLC}	Setup Time, IL to	Interface Latch Inputs Only	100			ns
-	CCLK 8 of Byte 1					
t _{HCL}	Hold Tme, IL Valid from		50			ns
	8th CCLK Low (Byte 1)					
t _{DCL}	Delay Time CCLK8 of	Interface Latch Outputs Only			200	ns
	Byte 2 to IL	C _L = 50 pF				



Timing Diagrams

www.ti.com









www.ti.com

Transmission Characteristics

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for $V_{CC} = +5V \pm 5\%$, $V_{BB} = -5V \pm 5\%$; $T_A = 0^{\circ}C$ to +70°C by correlation with 100% electrical testing at $T_A = 25^{\circ}C$. f = 1015.625 Hz, $VF_XI = 0$ dBm0, $D_R1 = 0$ dBm0 PCM code. Transmit and receive gains programmed for maximum 0 dBm0 test levels (0 dB Gain). All other limits are assured by correlation with other production tests and/or product design and characterization. All signals referenced to GND. Typicals specified at $V_{CC} = +5V$, $V_{BB} = -5V$, $T_A = 25^{\circ}C$.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
	JDE RESPONSE					
	Absolute Levels	The Maximum 0 dBm0 Levels Are:				
		VF _X I		1.375		Vrms
		VF _R O (15 kΩ Load)		1.964		Vrms
		The Minimum 0 dBm0 Levels are:				
		VF _X I		73.8		mVrms
		$VF_{R}O$ (Any Load $\geq 300\Omega$)		105.0		mVrms
G _{XA}	Transmit Gain	Transmit Gain Programmed for Maximum				
	Absolute Accuracy	0 dBm0 Test Level.				
		Measure Deviation of Digital Code from				
		Ideal 0 dBm0 PCM Code at D _X 1.				
		$T_A = 25^{\circ}C$	-0.15		0.15	dB
G _{XAG}	Transmit Gain	$T_A = 25^{\circ}C, V_{CC} = 5V, V_{BB} = 5V$				
	Variation with	Programmed Gain from 0 dB to 19 dB				
	Programmed Gain	(0 dBm0 Levels of 1.619 Vrms to 0.182 Vrms)	-0.1		0.1	dB
		Programmed Gain from 19.1 dB to 25.4 dB				
		(0 dBm0 Levels of 0.180 Vrms to 0.087 Vrms)	-0.3		0.3	dB
		±0.1 dB Min/Max is Available as a Selected Part				
G _{XAF}	Transmit Gain	Relative to 1015.625 Hz, ⁽¹⁾				
701	Variation with	Minimum Gain < G _X < Maximum Gain				
	Frequency	f = 60 Hz			-26	dB
		f = 200 Hz	-1.8		-0.1	dB
		f = 300 Hz to 3000 Hz	-0.15		0.15	dB
		f = 3400 Hz	-0.7		0.0	dB
		f = 400 Hz			-14	dB
		f ≥ 4600 Hz. Measure Response			-32	dB
		at Alias Frequency from 0 kHz to 4 kHz				
		G _X = 0.0 dB, VF _X I = 1.375 Vrms				
		Relative to 1015.625 Hz				
		f = 62.5 Hz			-24.9	dB
		f = 203.125 Hz	-1.7		-0.1	dB
		f = 343.75 Hz	-0.15		0.15	dB
		f = 515.625 Hz	-0.15		0.15	dB
		f = 2140.625 Hz	-0.15		0.15	dB
		f = 3156.25 Hz	-0.15		0.15	dB
		f = 3406.250 Hz	-0.74		0.0	dB
		f = 3984.375 Hz			-13.5	dB
		Relative to 1062.5 Hz ⁽¹⁾				

(1) A multi-tone test technique is used.

6 Submit Documentation Feedback

Copyright © 2004–2010, Texas Instruments Incorporated



www.ti.com

Transmission Characteristics (continued)

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for $V_{CC} = +5V \pm 5\%$, $V_{BB} = -5V \pm 5\%$; $T_A = 0^{\circ}C$ to +70°C by correlation with 100% electrical testing at $T_A = 25^{\circ}C$. f = 1015.625 Hz, $VF_XI = 0$ dBm0, $D_R1 = 0$ dBm0 PCM code. Transmit and receive gains programmed for maximum 0 dBm0 test levels (0 dB Gain). All other limits are assured by correlation with other production tests and/or product design and characterization. All signals referenced to GND. Typicals specified at $V_{CC} = +5V$, $V_{BB} = -5V$, $T_A = 25^{\circ}C$.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
		f = 5250 Hz, Measure 2750 Hz			-32	dB
		f = 11750 Hz, Measure 3750 Hz			-32	dB
		f = 49750 Hz, Measure 1750 Hz			-32	dB
G _{XAT}	Transmit Gain	Measured Relative to G_{XA} , $V_{CC} = 5V$,				
	Variation with	$V_{BB} = -5V,$	-0.1		0.1	dB
	Temperature	Minimum gain < G _X < Maximum Gain				
G _{XAL}	Transmit Gain	Sinusoidal Test Method.				
	Variation with	Reference Level = 0 dBm0				
	Signal Level	$VF_XI = -40 \text{ dBm0 to } +3 \text{ dBm0}$	-0.2		0.2	dB
		$VF_XI = -50 \text{ dBm0 to } -40 \text{ dBm0}$	-0.4		0.4	dB
		$VF_XI = -55 \text{ dBm0}$ to -50 dBm0	-1.2		1.2	dB
G _{RA}	Receive Gain	Receive Gain Programmed for Maximum				
	Absolute Accuracy	0 dBm0 Test Level. Apply 0 dBm0	-0.15		0.15	dB
		PCM Code to D _R 1. Measure VF _R 0.				
		$T_A = 25^{\circ}C$				
G _{RAG}	Receive Gain	$T_A = 25^{\circ}C, V_{CC} = 5V, V_{BB} = -5V$				
	Variation with	Programmed Gain from 0 dB to 19 dB				
	Programmed Gain	(0 dBm0 Levels of 1.964 Vrms to 0.220 Vrms)	-0.1		0.1	dB
		Programmed Gain from 19.1 dB to 25.4 dB				
		(0 dBm0 Levels of 0.218 Vrms to 0.105 Vrms)	-0.3		0.3	dB
		NOTE ±0.1 dB Min/Max is Available as a Selected Part				
G _{RAT}	Receive Gain	Measured Relative to G _{RA} .				
	Variation with	$V_{CC} = 5V, V_{BB} = -5V.$	-0.1		0.1	dB
	Temperature	Minimum Gain < G _R < Maximum Gain				
G _{RAF}	Receive Gain	Relative to 1015.625 Hz, ⁽²⁾				
	Variation with	$D_R 1 = 0 \text{ dBm0 Code.}$				
	Frequency	Minimum Gain < G _R < Maximum Gain				
		f = 200 Hz	-0.25		0.15	dB
		f = 300 Hz to 3000 Hz	-0.15		0.15	dB
		f = 3400 Hz	-0.7		0.0	dB
		f = 4000 Hz			-14	dB
		$G_R = 0 \text{ dB}, D_R 1 = 0 \text{ dBm} 0 \text{ Code},$				
		$G_X = 0 \text{ dB}^{(2)}$				
		f = 296.875 Hz	-0.15		0.15	dB
		f = 1875.00 Hz	-0.15		0.15	dB
		f = 2906.25 Hz	-0.15		0.15	dB
		f = 2984.375 Hz	-0.15		0.15	dB
		f = 3406.250 Hz	-0.74		0.0	dB

(2) A multi-tone test technique is used.

Copyright © 2004–2010, Texas Instruments Incorporated



www.ti.com

Transmission Characteristics (continued)

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for $V_{CC} = +5V \pm 5\%$, $V_{BB} = -5V \pm 5\%$; $T_A = 0^{\circ}C$ to +70°C by correlation with 100% electrical testing at $T_A = 25^{\circ}C$. f = 1015.625 Hz, $VF_XI = 0$ dBm0, $D_R1 = 0$ dBm0 PCM code. Transmit and receive gains programmed for maximum 0 dBm0 test levels (0 dB Gain). All other limits are assured by correlation with other production tests and/or product design and characterization. All signals referenced to GND. Typicals specified at $V_{CC} = +5V$, $V_{BB} = -5V$, $T_A = 25^{\circ}C$.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
		f = 3984.375 Hz			-13.5	dB
G _{RAL}	Receive Gain	Sinusoidal Test Method.				
	Variation with	Reference Level = 0 dBm0.				
	Signal Level	$D_R 1 = -40 \text{ dBm0 to } +3 \text{ dBm0}$	-0.2		0.2	dB
		$D_R 1 = -50 \text{ dBm0 to } -40 \text{ dBm0}$	-0.4		0.4	dB
		$D_{R}1 = -55 \text{ dBm0 to } -50 \text{ dBm0}$	-1.2		1.2	dB
		DR ₁ = 3.1 dBm0 −0.5				
		$R_{L} = 600\Omega, G_{R} = -0.5 \text{ dB}$	-0.2		0.2	dB
		R _L = 300Ω, G _R = 1.2 dB	-0.2		0.2	dB
ENVELO	PE DELAY DISTORTION WITH F	REQUENCY		•		•
D _{XA}	Tx Delay, Absolute	f = 1600 Hz			315	μs
D _{XR}	Tx Delay, Relative to DXA	f = 500 Hz–600 Hz			220	μs
		f = 600 Hz–800 Hz			145	μs
		f = 800 Hz–1000 Hz			75	μs
		f = 1000 Hz–1600 Hz			40	μs
		f = 1600 Hz–2600 Hz			75	μs
		f = 2600 Hz–2800 Hz			105	μs
		f = 2800 Hz–3000 Hz			155	μs
D _{RA}	Rx Delay, Absolute	f = 1600 Hz			200	μs
D _{RR}	Rx Delay, Relative to DRA	f = 500 Hz–1000 Hz	-40			μs
		f = 1000 Hz–1600 Hz	-30			μs
		f = 1600 Hz–2600 Hz			90	μs
		f = 2600 Hz–2800 Hz			125	μs
		f = 2800 Hz–3000 Hz			175	μs
NOISE	1			1		
N _{XC}	Transmit Noise, C Message	⁽³⁾ 1111111		12	15	dBrnC0
-	Weighted, µ-Law Selected	in Gain Register				
N _{XP}	Transmit Noise, P Message	(3) 1111111		-74	-67	dBm0p
	Weighted, A-Law Selected	in Gain Register				
N _{RC}	Receive Noise, C Message	PCM Code is Alternating Positive		8	11	dBrnC0
	Weighted, µ-Law Selected					
N _{RP}	Receive Noise, P Message	PCM Code Equals Positive Zero		-82	-79	dBm0p
	Weighted, A-Law Selected					
N _{RS}	Noise, Single Frequency	f = 0 kHz to 100 kHz, Loop Around			-53	dBm0
		Measurement, $VF_XI = 0$ Vrms				
PPSR _X	Positive Power Supply	$V_{CC} = 5.0 V_{DC} + 100 \text{ mVrms}$				
	Rejection, Transmit	$f = 0 \text{ kHz}-4 \text{ kHz}^{(4)}$	36			dBC
		f = 4 kHz–50 kHz	30			dBC
NPSR _X	Negative Power Supply	$V_{BB} = -5.0 V_{DC} + 100 \text{ mVrms}$				
	Rejection, Transmit	$f = 0 \text{ kHz} - 4 \text{ kHz}^{(4)}$	36			dBC
		f = 4 kHz–50 kHz	30			dBC

(3) Measured by grounded input at V_{FXI} .

(4) PPSR_X, NPSR_X, and CT_{R-X} are measured with a -50 dBm0 activation signal applied to VF_XI.



www.ti.com

Transmission Characteristics (continued)

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for $V_{CC} = +5V \pm 5\%$, $V_{BB} = -5V \pm 5\%$; $T_A = 0^{\circ}C$ to +70°C by correlation with 100% electrical testing at $T_A = 25^{\circ}C$. f = 1015.625 Hz, $VF_XI = 0$ dBm0, $D_R1 = 0$ dBm0 PCM code. Transmit and receive gains programmed for maximum 0 dBm0 test levels (0 dB Gain). All other limits are assured by correlation with other production tests and/or product design and characterization. All signals referenced to GND. Typicals specified at $V_{CC} = +5V$, $V_{BB} = -5V$, $T_A = 25^{\circ}C$.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
PPSR _R	Positive Power Supply	PCM Code Equals Positive Zero				
	Rejection, Receive	$V_{CC} = 5.0 V_{DC} + 100 \text{ mVrms}$				
		Measure VF _R O				
		f = 0 Hz–4000 Hz	36			dBC
		f = 4 kHz–25 kHz	40			dB
		f = 25 kHz–50 kHz	36			dB
NPSR _R	Negative Power Supply	PCM Code Equals Positive Zero				
	Rejection, Receive	$V_{BB} = -5.0 V_{DC} + 100 \text{ mVrms}$				
		Measure VF _R O				
		f = 0 Hz–4000 Hz	36			dBC
		f = 4 kHz–25 kHz	40			dB
		f = 25 kHz–50 kHz	36			dB
SOS	Spurous Out-of-Band	0 dBm0 300 Hz to 3400 Hz Input PCM Code				
	Signals Applied at the	at D _R 1				
	Channel Output	4600 Hz–7600 Hz			-30	dB
		7600 Hz–8400 Hz			-40	dB
		8400 Hz–50,000 Hz			-30	dB
DISTORT	ION			1	1	1
STD _X	Signal to Total Distortion	Sinusoidal Test Method				
STD _R	Transmit or Receive	Level = 3.0 dBm0	33			dBC
	Half-Channel, µ-Law	= 0 dBm0 to -30 dBm0	36			dBC
	Selected	= −40 dBm0	30			dBC
		= −45 dBm0	25			dBC
STD _{RL}	Single to Total Distortion	Sinusoidal Test Method				
	Receive with Resistive	Level = +3.1 dBm0				
	Load	$R_{L} = 600\Omega, G_{R} = -0.5 \text{ dB}$	33			dBC
		$R_{L} = 300\Omega, G_{R} = -1.2 \text{ dB}$	33			dBC
SFD _X	Single Frequency				-46	dB
	Distortion, Transmit					
SFD _R	Single Frequency				-46	dB
	Distortion, Receive					
IMD	Intermodulation Distortion	Transmit or Receive				
		Two Frequencies in the Range			-41	dB
		300 Hz–3400 Hz				
CROSST	ALK		I	ł	ł	+
CT _{X-R}	Transmit to Receive Crosstalk,	f = 300 Hz–3400 Hz		-90	-75	dB
	0 dBm0 Transmit Level	D _R = Idle Code				
CT _{R-X}	Receive to Transmit Crosstalk,	f = 300 Hz–3400 Hz		-90	-70	dB
	0 dBm0 Receive Level	(5)				

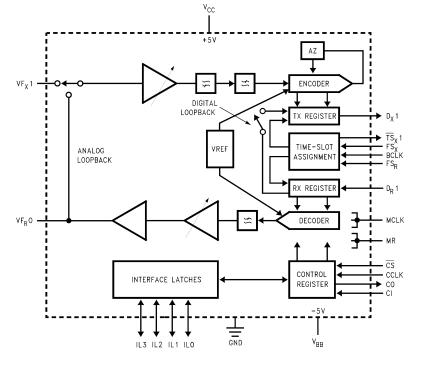
(5) PPSR_X, NPSR_X, and CT_{R-X} are measured with a -50 dBm0 activation signal applied to VF_XI.

TEXAS INSTRUMENTS

www.ti.com

SNOSC47C - MAY 2004 - REVISED JANUARY 2010

Block Diagram



Connection Diagram

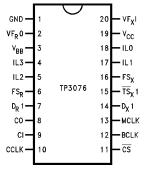


Figure 4.

10 Submit Documentation Feedback



OBSOLETE

www.ti.com

PIN FUNCTIONS

Pin Descriptions

Pin	Description
V _{cc}	+5V ±5% power supply.
V _{BB}	-5V ±5% power supply.
GND	Ground. All analog and digital signals are referenced to this pin.
FS _X	Transmit Frame Sync input. Normally a pulse or squarewave with an 8 kHz repetition rate is applied to this input to define the start of the transmit time slot assigned to this device (non-delayed data timing mode), or the start of the transmit frame (delayed data timing mode using the internal time-slot assignment counter).
FS _R	Receive Frame Sync input. Normally a pulse or squarewave with an 8 kHz repetition rate is applied to this input to define the start of the receive time slot assigned to this device (non-delayed data timing mode), or the start of the receive frame (delayed data timing mode using the internal time-slot assignment counter).
BCLK	Bit clock input used to shift PCM data into and out of the D _R and D _X pins. BCLK may vary from 64 kHz to 4.096 MHz in 8 kHz increments, and must be synchronous with MCLK.
MCLK	Master clock input used by the switched capacitor filters and the encoder and decoder sequencing logic. Must be 512 kHz, 1.536/1.544 MHz, 2.048 MHz or 4.096 MHz and synchronous with BCLK.
VF _X I	The Transmit analog high-impedance input. Voice frequency signals present on this input are encoded as an A-law or μ -law PCM bit stream and shifted out on the selected D _X pin.
VF _R O	The Receive analog power amplifier output, capable of driving load impedances as low as 300Ω (depending on the peak overload level required). PCM data received on the assigned D _R pin is decoded and appears at this output as voice frequency signals.
D _X 1	This transmit data TRI-STATE [®] output remains in the high impedance state except during the assigned transmit time slot on the assigned port, during which the transmit PCM data byte is shifted out on the rising edges of BCLK.
TS _X 1	Normally this open drain output is floating in a high impedance state except when a time-slot is active on the D_X output, when the \overline{TS}_X 1 output pulls low to enable a backplane line-driver.
D _R 1	This receive data input is inactive except during the assigned receive time slot of the assigned port when the receive PCM data is shifted in on the falling edges of BCLK.
CCLK	Control Clock input. This clock shifts serial control information into CI or out from CO when the CS input is low, depending on the current instruction. CCLK may be asynchronous with the other system clocks.
CI	Control Data Input pin. Serial control information is shifted into COMBO II on this pin when \overline{CS} is low. Byte 1 of control information is always written into COMBO II, while the direction of byte 2 data is determined by bit 2 of byte 1, as defined in Table 1
со	Control Data Output pin. Serial control or status information is shifted out of COMBO II on this pin when CS is low.
CS	Chip Select input. When this pin is low, control information can be written to or read from COMBO II via CI or CO.
IL3–IL0	Each Interface Latch I/O pin may be individually programmed as an input or an output determined by the state of the corresponding bit in the Latch Direction Register (LDR). For pins configured as inputs, the logic state sensed on each input is latched into the Interface Latch Register (ILR) whenever control data is written to COMBO II, while CS is low, and the information is shifted out on the CO pin. When configured as outputs, control data written into the ILR appears at the corresponding IL pins.

SNOSC47C - MAY 2004 - REVISED JANUARY 2010

FUNCTIONAL DESCRIPTION

POWER-ON INITIALIZATION

When power is first applied, power-on reset circuitry initializes the COMBO II and puts it into the power-down state. The gain control registers for the transmit and receive gain sections are programmed for no output, the power amp is disabled and the device is in the non-delayed timing mode. The Latch Direction Register (LDR) is pre-set with all IL pins programmed as inputs, placing the SLIC interface pins in a high impedance state. The CO pin is in TRI-STATE condition. Other initial states in the Control Register are indicated in Section 2.0.

The desired modes for all programmable functions may be initialized via the control port prior to a Power-up command.

POWER-DOWN STATE

Following a period of activity in the powered-up state the power-down state may be re-entered by writing any of the control instructions into the serial control port with the "P" bit set to "1" as indicated in Table 1. It is recommended that the chip be powered down before writing any additional instructions. In the power-down state, all non-essential circuitry is de-activated and the D_x1 output is in the high impedance TRI-STATE condition.

The data stored in the Gain Control registers, the LDR and ILR, and all control bits remain unchanged in the power-down state unless changed by writing new data via the serial control port, which remains active. The outputs of the Interface Latches also remain active, maintaining the ability to monitor and control the SLIC.

TRANSMIT FILTER AND ENCODER

The Transmit section input, VF_XI , is a high impedance input. No external components are necessary to set the gain. Following this is a programmable gain/attenuation amplifier which is controlled by the contents of the Transmit Gain Register (see Programmable Functions section). An active pre-filter then precedes the 3rd order high-pass and 5th order low-pass switched capacitor filters. The A/D converter has a compressing characteristic according to the standard CCITT A or µ255 coding laws, which must be selected by a control instruction during initialization (see Table 1 and Table 2). A precision on-chip voltage reference ensures accurate and highly stable transmission levels. Any offset voltage arising in the gain-set amplifier, the filters or the comparator is canceled by an internal auto-zero circuit.

Each encode cycle begins immediately following the assigned Transmit time-slot. The total signal delay referenced to the start of the time-slot is approximately 165 μ s (due to the Transmit Filter) plus 125 μ s (due to encoding delay), which totals 290 μ s. Data is shifted out on D_X1 during the selected time slot on eight rising edges of BCLK.



www.ti.com

DECODER AND RECEIVER FILTER

PCM data is shifted into the Decoder's Receive PCM Register via the D_R1 pin during the selected time-slot on the 8 falling edges of BCLK. The Decoder consists of an expanding DAC with either A or µ255 law decoding characteristic, which is selected by the same control instruction used to select the Encode law during initialization. Following the Decoder is a 5th order low-pass switched capacitor filter with integral Sin x/x correction for the 8 kHz sample and hold. A programmable gain amplifier, which must be set by writing to the Receive Gain Register, is included, and finally a Power Amplifier capable of driving a 300 Ω load to ±3.5V, a 600 Ω load to ±3.8V or a 15 k Ω load to ±4.0V at peak overload.

Function			В	yte 1	(1) (2)	(3)			Byte 2 ⁽¹⁾							
	7	6	5	4	3	2	1	0	7	6	5	4	3	2	1	0
Single Byte Power-Up/Down	Р	Х	Х	Х	Х	Х	0	Х				No	one			
Write Control Register	Р	0	0	0	0	0	1	Х				See 7	able 2	2		
Read-Back Control Register	Р	0	0	0	0	1	1	Х				See 7	able 2	2		
Write to Interface Latch Register	Р	0	0	0	1	0	1	Х				See 7	able 4	1		
Read Interface Latch Register	Р	0	0	0	1	1	1	Х				See 7	able 4	1		
Write Latch Direction Register	Р	0	0	1	0	0	1	Х				See 7	able 3	3		
Read Latch Direction Register	Р	0	0	1	0	1	1	Х				See 7	able 3	3		
Write Receive Gain Register	Р	0	1	0	0	0	1	Х				See 7	able 8	3		
Read Receive Gain Register	Р	0	1	0	0	1	1	Х				See 7	able 8	3		
Write Transmit Gain Register	Р	0	1	0	1	0	1	Х				See 7	able 7	7		
Read Transmit Gain Register	Р	0	1	0	1	1	1	Х				See 7	able 7	7		
Write Receive Time-Slot/Port	Р	1	0	0	1	0	1	Х				See 7	able 6	6		
Read-Back Receive Time-Slot/Port	Р	1	0	0	1	1	1	Х	See Table 6					-		
Write Transmit Time-Slot/Port	Р	1	0	1	0	0	1	Х	See Table 6							
Read-Back Transmit Time-Slot/Port	Р	1	0	1	0	1	1	Х				See 7	able 6	6		

Table 1. Programmable Register Instructions

(1) Bit 7 of bytes 1 and 2 is always the first bit clocked into or out from the CI or CO pin. X = don't care.

(2) "P" is the power-up/down control bit, see Power-up/Down Control section. ("0" = Power Up, "1" = Power Down)

(3) Other register address codes are invalid and should not be used.

A decode cycle begins immediately after the assigned receive timeslot, and 10 μ s later the Decoder DAC output is updated. The total signal delay is 10 μ s plus 120 μ s (filter delay) plus 62.5 μ s (½ frame) which gives approximately 190 μ s.



PCM INTERFACE

SNOSC47C-MAY 2004-REVISED JANUARY 2010

The FS_X and FS_R frame sync inputs determine the beginning of the 8-bit transmit and receive time-slots respectively. They may have any duration from a single cycle of BCLK HIGH to one MCLK period LOW. Two different relationships may be established between the frame sync inputs and the actual time-slots on the PCM busses by setting bit 3 in the Control Register (see Table 2). Non-delayed data mode is similar to long-frame timing on the TP3050/60 series of devices (COMBO); time-slots begin nominally coincident with the rising edge of the appropriate FS input. The alternative is to use Delayed Data mode, which is similar to shortframe sync timing on COMBO, in which each FS input must be high at least a half-cycle of BCLK earlier than the timeslot. The Time-Slot Assignment circuit on the device can only be used with Delayed Data timing.

When using Time-Slot Assignment, the beginning of the first time-slot in a frame is identified by the appropriate FS input. The actual transmit and receive time-slots are then determined by the internal Time-Slot Assignment counters.

Transmit and Receive frames and time-slots may be skewed from each other by any number of BCLK cycles. During each assigned Transmit time-slot, the D_X1 output shifts data out from the PCM register on the rising edges of BCLK. \overline{TS}_X1 also pulls low for the first 7½ bit times of the time-slot to control the TRI-STATE Enable of a backplane line-driver. Serial PCM data is shifted into the D_R1 input during each assigned Receive time-slot on the falling edges of BCLK.

SERIAL CONTROL PORT

Control information and data are written into or read-back from COMBO II via the serial control port consisting of the control clock CCLK, the serial data input, CI, and output, CO, and the Chip Select input, \overline{CS} . All control instructions require 2 bytes, as listed Table 1, with the exception of a single byte power-up/down command. The Byte 1 bits are used as follows: bit 7 specifies power up or power down; bits 6, 5, 4 and 3 specify the register address, bit 2 specifies whether the instruction is read or write; bit 1 specifies a one or two byte instruction; and bit 0 is not used.

To shift control data into COMBO II, CCLK must be pulsed high 8 times while \overline{CS} is low. Data on the CI input is shifted into the serial input register on the falling edge of each CCLK pulse. After all data is shifted in, the contents of the input shift register are decoded, and may indicate that a 2nd byte of control data will follow. This second byte may either be defined by a second byte-wide \overline{CS} pulse or may follow the first contiguously, i.e, it is not mandatory for \overline{CS} to return high between the first and second control bytes. At the end of CCLK8 in the 2nd control byte the data is loaded into the appropriate programmable register. \overline{CS} may remain low continuously when programming successive registers, if desired. However, \overline{CS} must be set high when no data transfers are in progress.

To readback Interface Latch data or status information from COMBO II, the first byte of the appropriate instruction is strobed while CS is low, as defined in Table 1. CS must be kept low, or be taken low again for a further 8 CCLK cycles, during which the data is shifted onto the CO pin on the rising edges of CCLK. When CS is high the CO pin is in the high-impedance TRI-STATE, enabling the CI and CO pins of many devices to be multiplexed together.

If \overline{CS} returns high during either byte 1 or byte 2 before all eight CCLK pulses of that byte occur, both the bit count and byte count are reset and register contents are not affected. This prevents loss of synchronization in the control interface as well as corruption of register data due to processor interrupt or other problem. When \overline{CS} returns low again, the device will be ready to accept bit 1 of byte 1 of a new instruction.



PROGRAMMABLE FUNCTIONS

POWER-UP/DOWN CONTROL

Following power-on initialization, power-up and power-down control may be accomplished by writing any of the control instructions listed in Table 1 into COMBO II with the "P" bit set to "0" for power-up or "1" for power-down. Normally it is recommended that all programmable functions be initially programmed while the device is powered down. Power state control can then be included with the last programming instruction or the separate single-byte instruction. Any of the programmable registers may also be modified while the device is powered-up or down by setting the "P" bit as indicated. When the power-up or down control is entered as a single byte instruction, bit one (1) must be reset to a 0.

When a power-up command is given, all de-activated circuits are activated, but the TRI-STATE PCM output(s), D_X1 will remain in the high impedance state until the second FS_x pulse after power-up.

CONTROL REGISTER INSTRUCTION

The first byte of a READ or WRITE instruction to the Control Register is as shown in Table 1. The second byte has the following bit functions:

		E	Bit Numbe	r and Nam	e			
7	6	5	4	3	2	1	0	Function
F ₁	Fo	MA	IA	DN	DL	AL	PP	
0	0							MCLK = 512 kHz
0	1							MCLK = 1.536 MHz
								or 1.544 MHz
1	0							MCLK = 2.048 MHz ⁽¹⁾
1	1							MCLK = 4.096 MHz
		0	Х					Select µ255 Law ⁽¹⁾
		1	0					A-Law, Including
								Even Bit
								Inversion
		1	1					A-Law, No Even Bit
								Inversion
				0				Delay Data Timing
				1				Non-Delayed
								Data Timing ⁽¹⁾
					0	0		Normal Operation ⁽¹⁾
					1	Х		Digital Loopback
					0	1		Analog Loopback
							0	Power Amp
								Enabled in PDN
							1	Power Amp
								Disabled in PDN ⁽¹⁾

Table 2. Control Register Byte 2 Functions

(1) state at power-on initialization.

Master Clock Frequency Selection

A Master clock must be provided to COMBO II for operation of the filter and coding/decoding functions. The MCLK frequency must be either 512 kHz, 1.536 MHz, 1.544 MHz, 2.048 MHz, or 4.096 MHz and must be synchronous with BCLK. Bits F_1 and F_0 (see Table 2) must be set during initialization to select the correct internal divider.

Copyright © 2004–2010, Texas Instruments Incorporated



Coding Law Selection

Bits "MA" and "IA" in Table 2 permit the selection of μ 255 coding or A-law coding, with or without even bit inversion.

Analog Loopback

Analog Loopback mode is entered by setting the "AL" and "DL" bits in the Control Register as shown in Table 2. In the analog loopback mode, the Transmit input VF_XI is isolated from the input pin and internally connected to the VF_RO output, forming a loop from the Receive PCM Register back to the Transmit PCM Register. The VF_RO pin remains active, and the programmed settings of the Transmit and Receive gains remain unchanged, thus care must be taken to ensure that overload levels are not exceeded anywhere in the loop.

Digital Loopback

Digital Loopback mode is entered by setting the "AL" and "DL" bits in the Control Register as shown in Table 2. This mode provides another stage of path verification by enabling data written into the Receive PCM Register to be read back from that register in any Transmit time-slot at D_X1 . PCM decoding continues and analog output appears at VF_R0. The output can be disabled by programming 'No Output' in the Receive Gain Register (see Table 8).

INTERFACE LATCH DIRECTIONS

Immediately following power-on, all Interface Latches assume they are inputs, and therefore all IL pins are in a high impedance state. Each IL pin may be individually programmed as a logic input or output by writing the appropriate instruction to the LDR, see Table 1 and Table 3. For minimum power dissipation, unconnected latch pins should be programmed as outputs. For the TP3076, bits 2 and 3 should always be programmed as "1" (outputs).

Bits L_3-L_0 must be set by writing the specific instruction to the LDR with the L bits in the second byte set as follows:

	Byte 2 Bit Number											
7	6	5 4 3 2 1										
L ₀	L ₁	L ₂	L ₃	1	1	х	X					
	L _n	Bit		IL Direction								
	()			Inp	out						
	1	1			Out	iput						

Table 3. Byte 2 Functions of Latch Direction Register⁽¹⁾

(1) X = Don't Care



INTERFACE LATCH STATES

Interface Latches configured as outputs assume the state determined by the appropriate data bit in the 2-byte instruction written to the Interface Latch Register (ILR) as shown in Table 1 and Table 4. Latches configured as inputs will sense the state applied by an external source, such as the Off-Hook detect output of a SLIC. All bits of the ILR, i.e. sensed inputs and the programmed state of outputs, can be read back in the 2nd byte of a READ from the ILR.

It is recommended that during initialization, the state of IL pins to be configured as outputs should be programmed first followed immediately by the Latch Direction Register.

Table 4. Interface Latch Data Bit Order

Bit Number							
7	6	5	4	3	2	1	0
D ₀	D ₁	D ₂	D ₃	D ₄	D_5	Х	Х

Table 5. Coding Law Conventions⁽¹⁾

	μ255 Law	True A-Law with	A-Law without Even Bit Inversion	
		Even Bit Inversion		
	MSB LSB	MSB LSB	MSB LSB	
V _{IN} = +Full Scale	1000000	10101010	11111111	
$V_{IN} = 0V$	1111111	11010101	10000000	
	1111111	01010101	0 0 0 0 0 0 0 0 0	
V _{IN} = -Full Scale	0000000	00101010	011111111	

(1) The MSB is always the first PCM bit shifted in or out of COMBO II.

Table 6. Time-Slot and Port Assignment Instruction

Bit Number and Name							Function	
7	6	5	4	3	2	1	0	
EN	PS	T ₅	T ₄	T ₃	T ₂	T ₁	T ₀	
	(1)	(2)						
0	1	Х	Х	X X X X X		Х	Disable D _X 1 Output (Transmit Instruction)	
								Disable D _R 1 Input (Receive Instruction)
1	1	Assign One Binary Coded Time-Slot from 0-63			n 0–63	Enable D _X 1 Output (Transmit Instruction)		
		Assign One Binary Coded Time-Slot from 0–63				n 0–63	Enable D _R 1 Input (Transmit Instruction)	

(1) The "PS" bit MUST be set to "1" for both transmit and receive for the TP3076.

(2) T5 is the MSB of the time-slot assignment bit field. Time-slot bits should be set to "000000" for both transmit and receive when operating in non-delayed data timing mode.



www.ti.com

TIME-SLOT ASSIGNMENT

COMBO II can operate in either fixed time-slot or time-slot assignment mode for selecting the Transmit and Receive PCM time-slots. Following power-on, the device is automatically in Non-Delayed Timing mode, in which the time-slot always begins with the leading (rising) edge of frame sync inputs FS_X and FS_R . Time-Slot Assignment may only be used with Delay Data timing; see Figure 2. FS_X and FS_R may have any phase relationship with each other in BCLK period increments.

Alternatively, the internal time-slot assignment counters and comparators can be used to access any time-slot in a frame, using the frame sync inputs as marker pulses for the beginning of transmit and receive time-slot 0. In this mode, a frame may consist of up to 64 time-slots of 8 bits each. A time-slot is assigned by a 2-byte instruction as shown in Table 1 and Table 6. The last 6 bits of the second byte indicate the selected time-slot from 0–63 using straight binary notation. When writing a time-slot and port assignment register, if the PCM interface is currently active, it is immediately deactivated to prevent possible bus clashes. A new assignment becomes active on the second frame following the end of the Chip-Select for the second control byte. Rewriting of the register contents should not be performed during the talking period of a connection to prevent waveform distortion caused by loss of a sample which will occur with each register write. The "EN" bit allows the PCM input, D_R1 , or output, D_X1 , as appropriate, to be enabled or disabled.

Time-Slot Assignment mode requires that the FS_X and FS_R pulses conform to the delayed data timing format shown in Figure 2.

PORT SELECTION

On the TP3076, the "PS" bit MUST always be set to 1.

Table 6 shows the format for the second byte of both transmit and receive time-slot and port assignment instructions.

OBSOLETE



SNOSC47C - MAY 2004 - REVISED JANUARY 2010

www.ti.com

TRANSMIT GAIN INSTRUCTION BYTE 2

The transmit gain can be programmed in 0.1 dB steps by writing to the Transmit Gain Register as defined in Table 1 and Table 7. This corresponds to a range of 0 dBm0 levels at VF_XI between 1.375 Vrms and 0.074 Vrms (equivalent to +5.0 dBm to -20.4 dBm in 600 Ω).

To calculate the binary code for byte 2 of this instruction for any desired input 0 dBm0 level in Vrms, take the nearest integer to the decimal number given by:

200 × log₁₀ (V/0.07299)

(1)

and convert to the binary equivalent. Some examples are given in Table 7. A complete tabulation is given in Appendix I of AN-614.

It should be noted that the Transmit (idle channel) Noise and Transmit Signal to Total Distortion are both specified with transmit gain set to 0 dB (gain register set to all ones). At high transmit gains there will be some degradation in noise performance for these parameters. See Application Note AN-614 for more information on this subject.

Table 7.	Byte 2 of	Transmit G	ain Instruction
----------	-----------	------------	-----------------

Bit Number	0 dBm0 Test Level (Vrms)
76543210	at VF _X I
0000000	No Output ⁽¹⁾
0000001	0.074
0000010	0.075
—	—
1111110	1.359
1111111	1.375

(1) Analog signal path is cut off, but D_X remains active and will output codes representing idle noise.

(2)

SNOSC47C - MAY 2004 - REVISED JANUARY 2010

RECEIVE GAIN INSTRUCTION BYTE 2

The receive gain can be programmed in 0.1 dB steps by writing to the Receive Gain Register as defined in Table 1 and Table 8. Note the following restrictions on output drive capability:

- 0 dBm0 levels ≤ 1.96 Vrms at VF_RO may be driven into a load of ≥ 15 kΩ to GND; Receive Gain set to 0 dB (gain register set to all ones).
- 2. 0 dBm0 levels ≤ 1.85 Vrms at VF_RO may be driven into a load of ≥ 600 Ω to GND; Receive Gain set to 0.5 dB.
- 3. 0 dBm0 levels \leq 1.71 Vrms at VF_RO may be driven into a load of \geq 300 Ω to GND. Receive Gain set to -1.2 dB.

To calculate the binary code for byte 2 of this instruction for any desired output 0 dBm0 level in Vrms, take the nearest integer to the decimal number given by:

200 × log₁₀ (V/0.1043)

and convert to the binary equivalent. Some examples are given in Table 8. A complete tabulation is given in Appendix I or AN-614.

Bit Number	0 dBm0 Test Level (Vrms)
76543210	at VF _R O
0000000	No Output (Low Z to GND)
0000001	0.105
0000010	0.107
_	_
1111110	1.941
1111111	1.964

Table 8. Byte 2 of Receive Gain Instruction



www.ti.com

APPLICATIONS INFORMATION

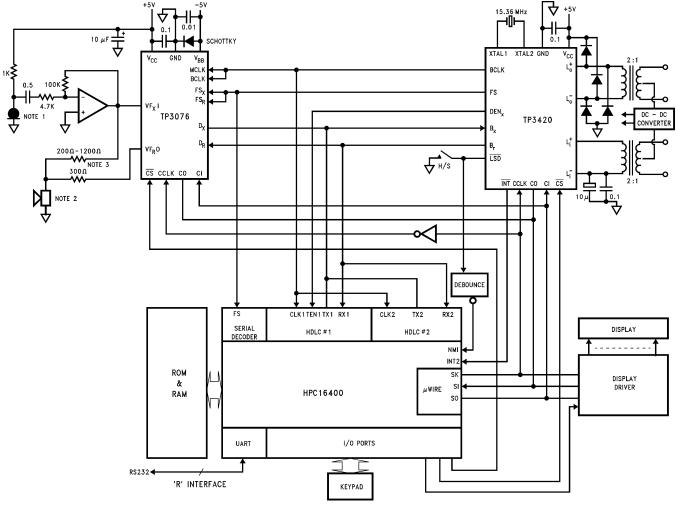
Figure 5 shows a typical ISDN phone application of the TP3076 together with a TP3420 ISDN Transceiver "S" Interface Device and HPC16400 High-Performance Microcontroller with HDLC Controller. The TP3076 device is programmed over its serial control interface via the HPC16400 MICROWIRE/PLUS™ serial I/O port.

POWER SUPPLIES

While the pins of the TP3076 COMBO II device are well protected against electrical misuse, it is recommended that the standard CMOS practice of applying GND to the device before any other connections are made should always be followed. In applications where the printed circuit card may be plugged into a hot socket with power and clocks already present, an extra long ground pin on the connector should be used and a Schottky diode connected between V_{BB} and GND.

To minimize noise sources all ground connections to each device should meet at a common point as close as possible to the GND pin in order to prevent the interaction of ground return currents flowing through a common bus impedance. Power supply decoupling capacitors of 0.1 μ F should be connected from this common point to V_{CC} and V_{BB} as close to the device pins as possible.

Further guidelines on PCB layout techniques are provided in Application Note AN-614, " COMBO II[™] Programmable PCM CODEC/Filter Family Application Guide".



- (1) Primo type EM80–PMI2 or similar.
- (2) Primo type DH31 or similar.
- (3) Sidetone ≈ -9.2 dB for 200 Ω ,Sidetone ≈ -21.5 dB for 1200 Ω .

Figure 5. Typical Application in an ISDN Phone

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products		Applications	
Audio	www.ti.com/audio	Automotive and Transportation	www.ti.com/automotive
Amplifiers	amplifier.ti.com	Communications and Telecom	www.ti.com/communications
Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy
Clocks and Timers	www.ti.com/clocks	Industrial	www.ti.com/industrial
Interface	interface.ti.com	Medical	www.ti.com/medical
Logic	logic.ti.com	Security	www.ti.com/security
Power Mgmt	power.ti.com	Space, Avionics and Defense	www.ti.com/space-avionics-defense
Microcontrollers	microcontroller.ti.com	Video and Imaging	www.ti.com/video
RFID	www.ti-rfid.com		
OMAP Applications Processors	www.ti.com/omap	TI E2E Community	e2e.ti.com
Wireless Connectivity	www.ti.com/wirelessconne	ectivity	

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2012, Texas Instruments Incorporated